

Notice of References Cited	Application/Control No. 10/597,853		Applicant(s)/Patent Under Reexamination ODAKA ET AL.	
	Examiner John P. Sheehan		Art Unit 1793	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2006/0016515	01-2006	Tomizawa et al.	148/101
*	C	US-2005/0016632	01-2005	Tomizawa et al.	148/105
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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